

# Noise Isolation

Keeping the Gremlins Out!

Cyrus Bazeghi

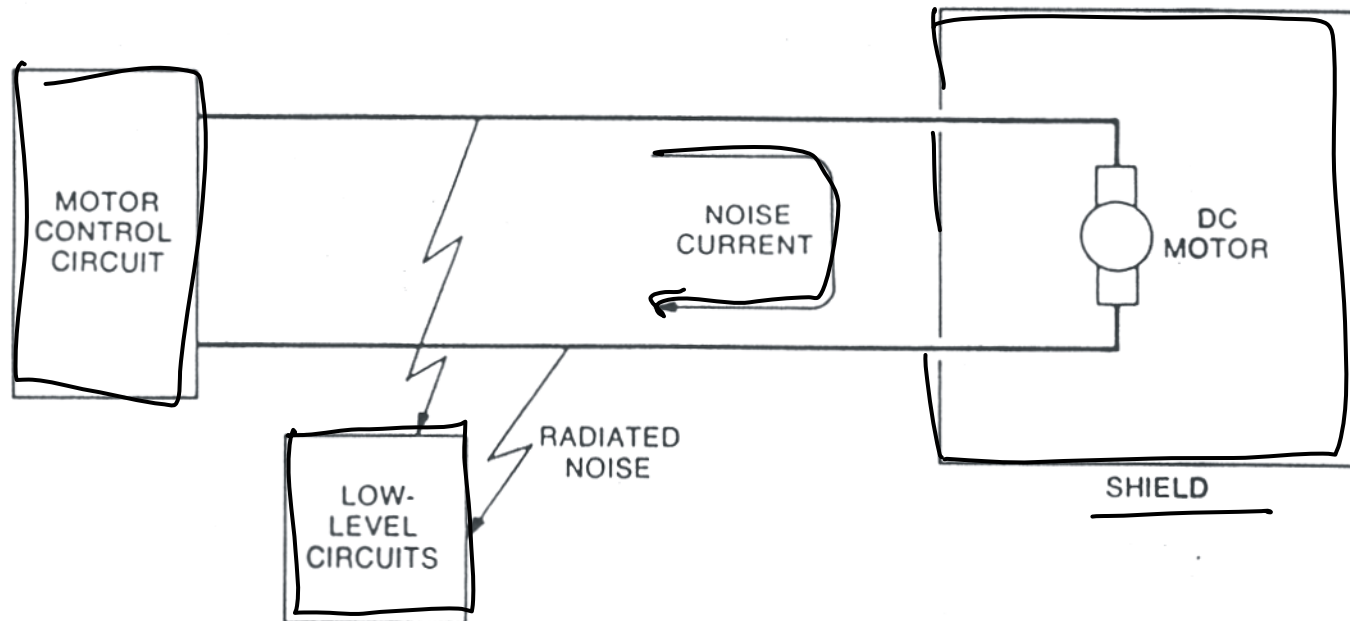
Winter 2010



# How noise gets into your circuits

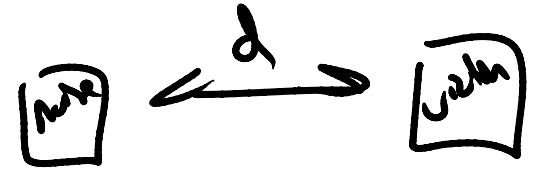


Figure 1-11. Before noise can be a problem, there must be a noise source, a receptor that is susceptible to the noise, and a coupling channel that transmits the noise to the receptor.



# Key Characteristics of the noise source

- Voltage  $\left\{ \begin{array}{l} \text{High Voltage, electric field} \\ \text{"capacitive coupling"} \\ \text{High } dV/dt \end{array} \right. \quad I = \frac{dV}{dt} C$
- Current - High Current gives "magnetic field" "inductive coupling"
- Frequency - High Freq - radiation - "radiation coupling"



- Distance from the victim -   
 ~~Number of direct sound~~   
 ~~+~~

$0 < \text{distance} < \text{wavelength}$   
 "p.f. coupling"  
 $0 = \text{distance}$   
 "conductive direct contact coupling"

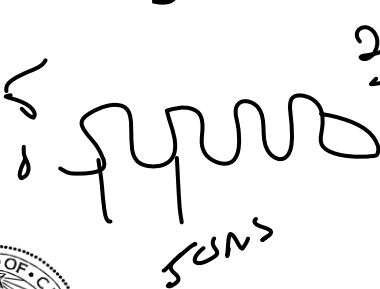


# What is the most likely coupling mechanism for:

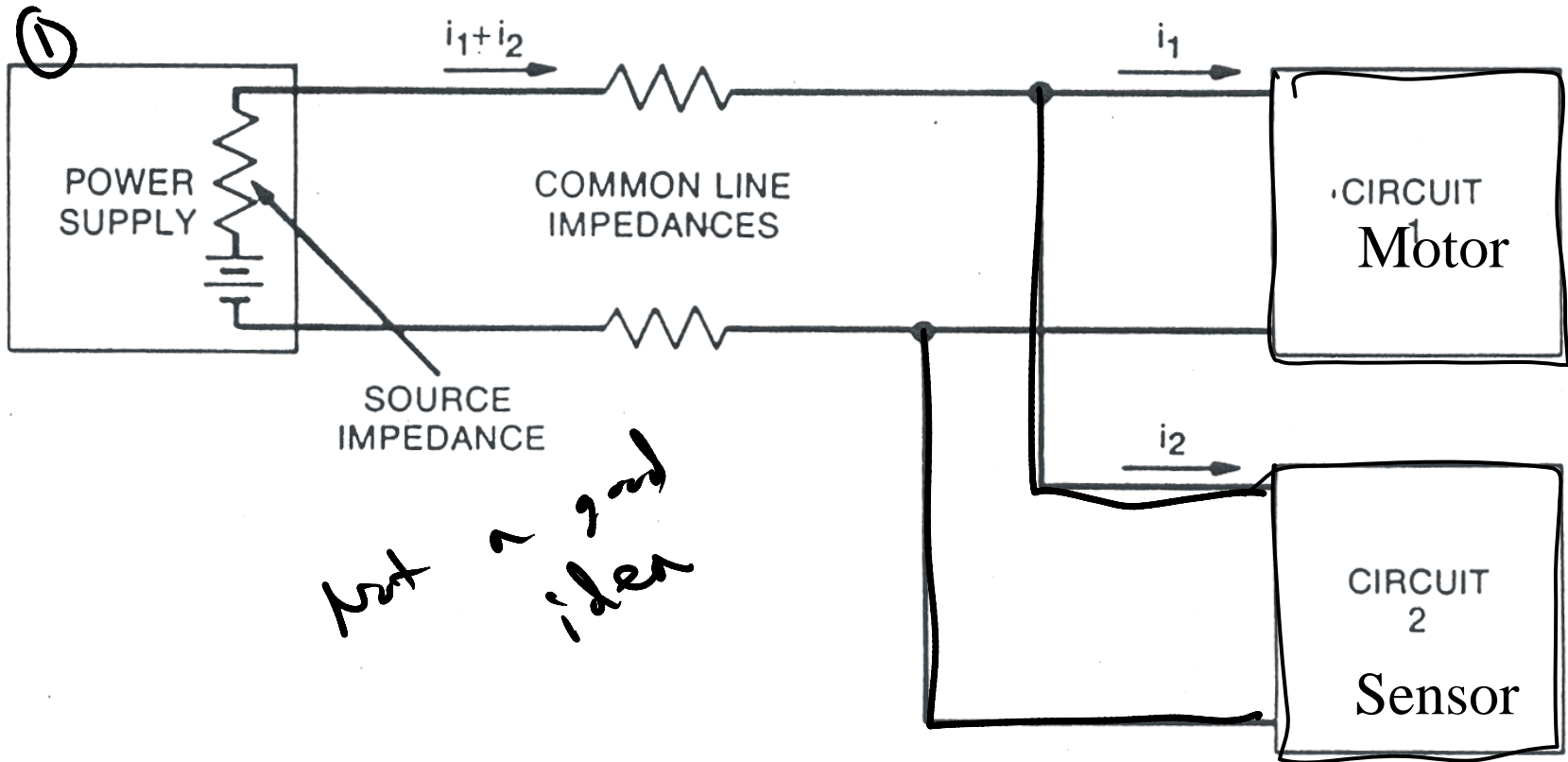
- Florescent Light noise  $\text{high } \frac{dV}{dt}$  "capacitive coupling"

- Arc Welding Noise  high current 100's of Amps "inductive coupling"

- Digital Clock Noise  $\frac{dV}{dt}$  High "capacitive coupling"



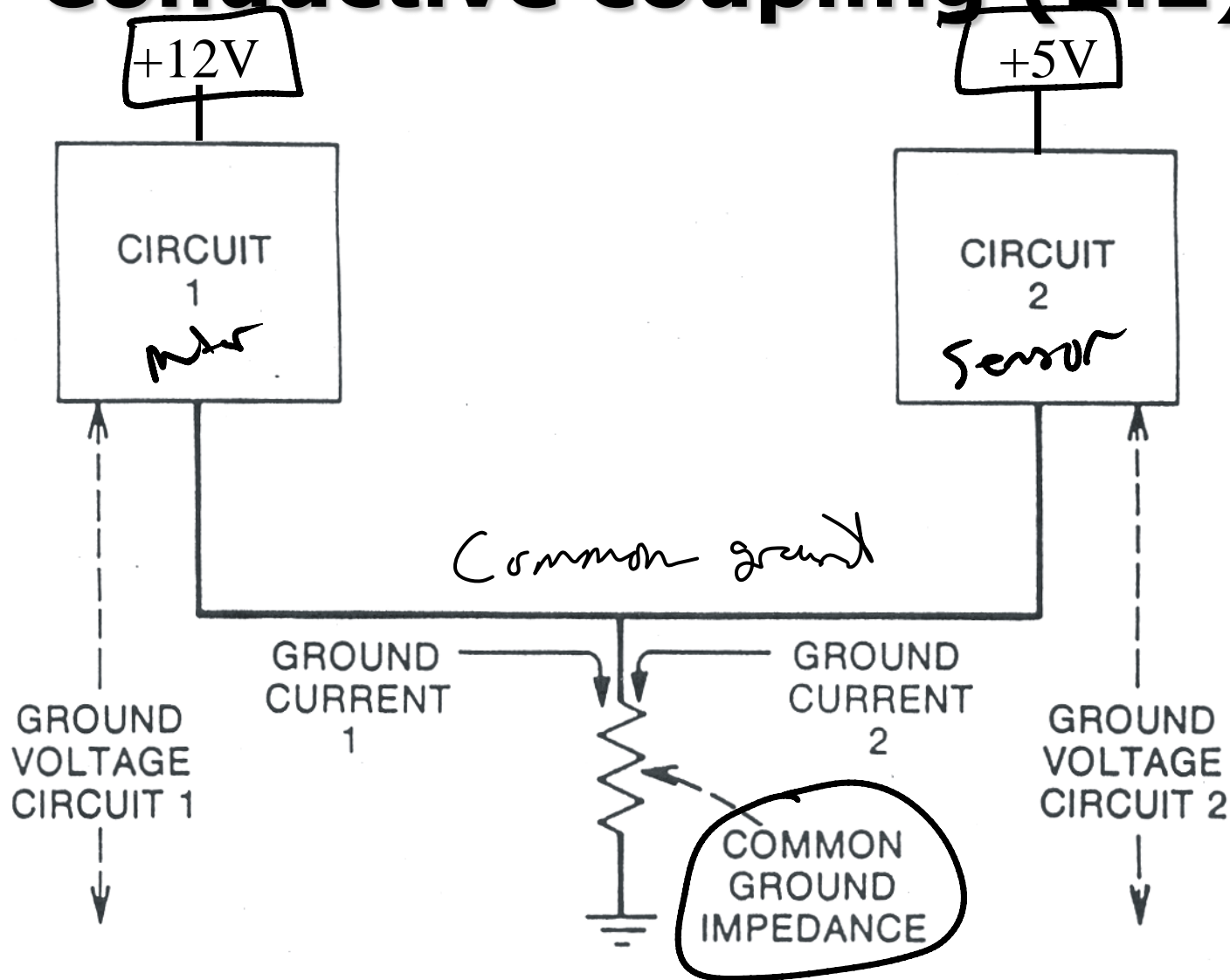
# Conductive coupling (1.2)



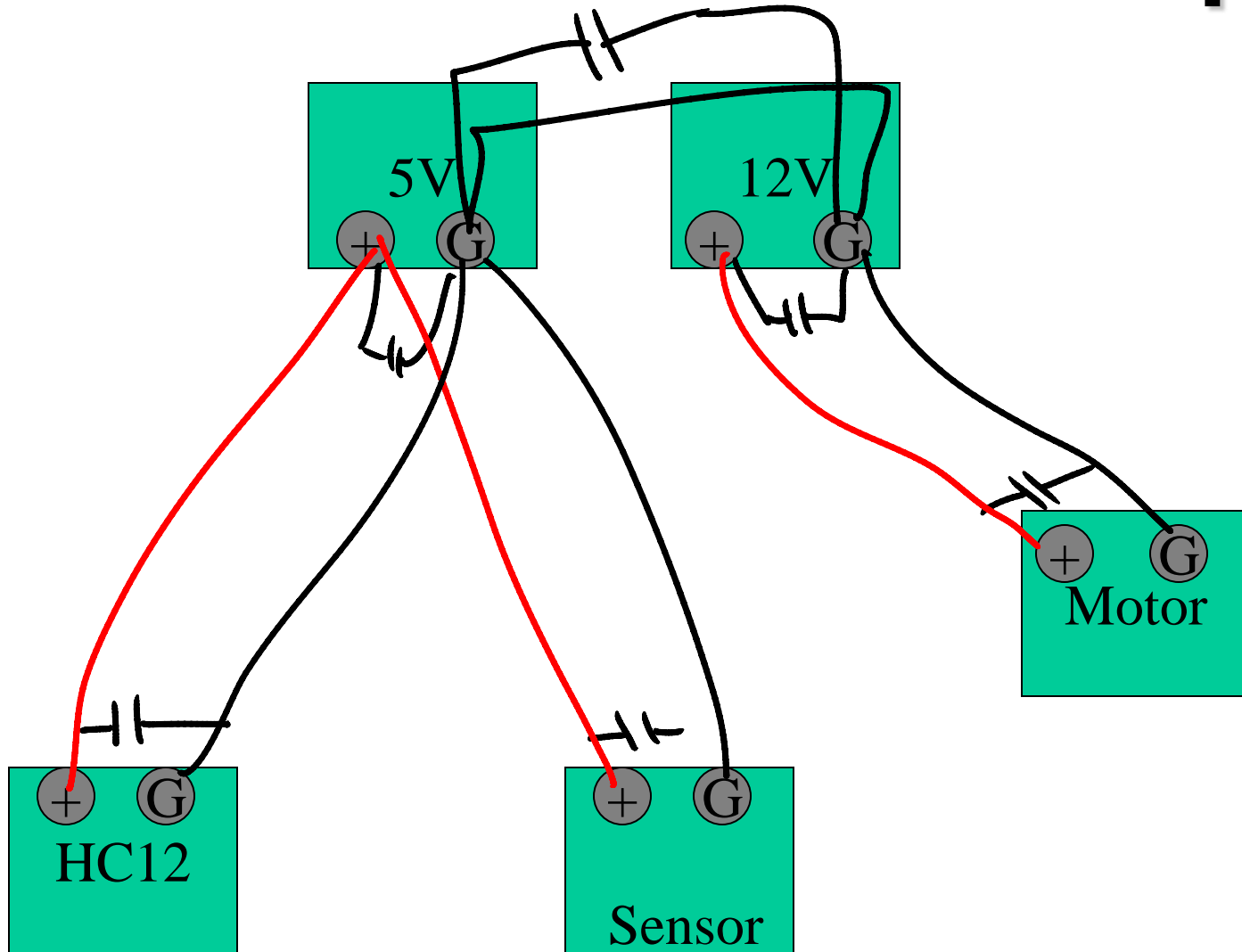
but ~ 2nd  
idea



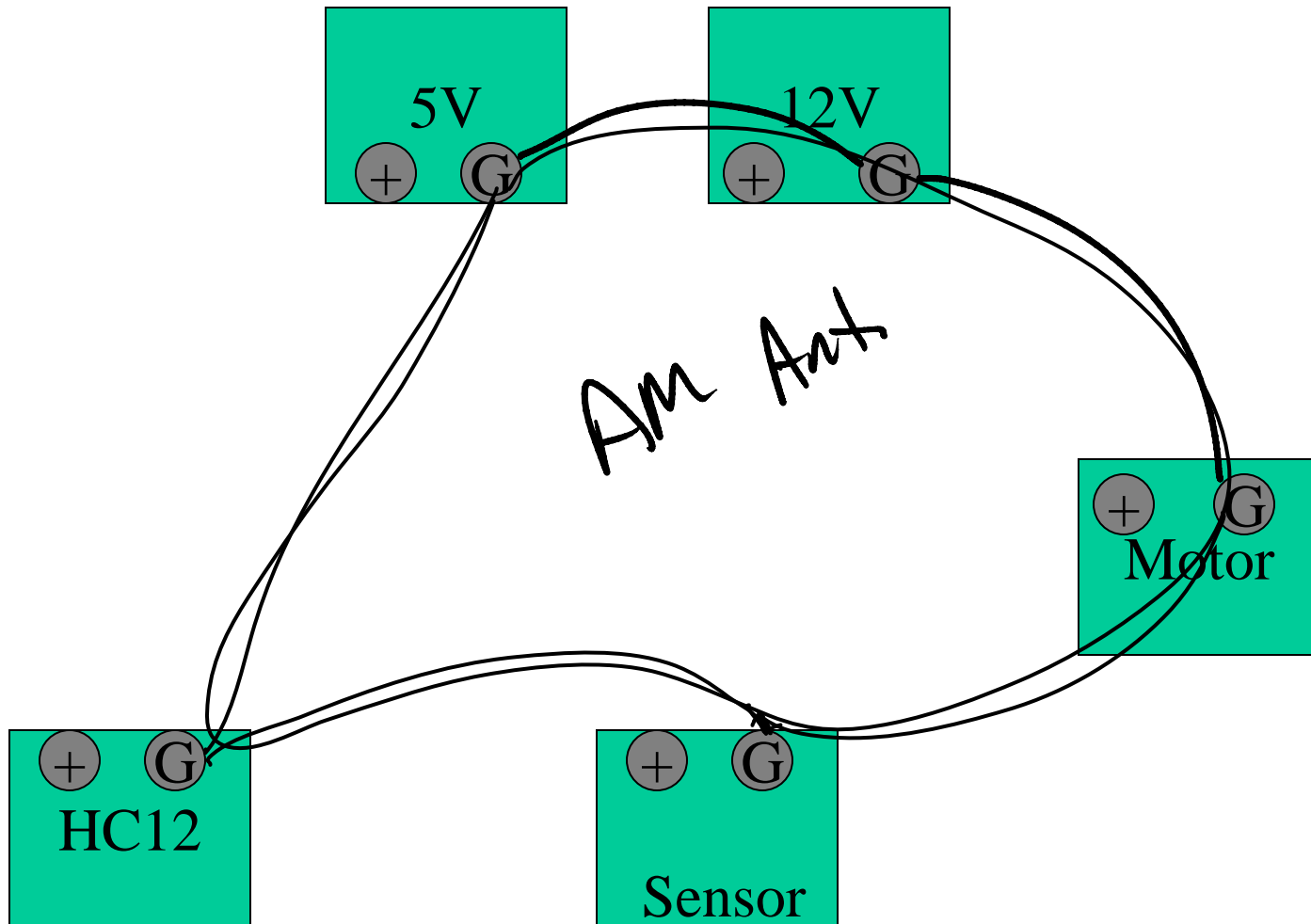
# Conductive coupling (2.2)



# How should I wire these up?

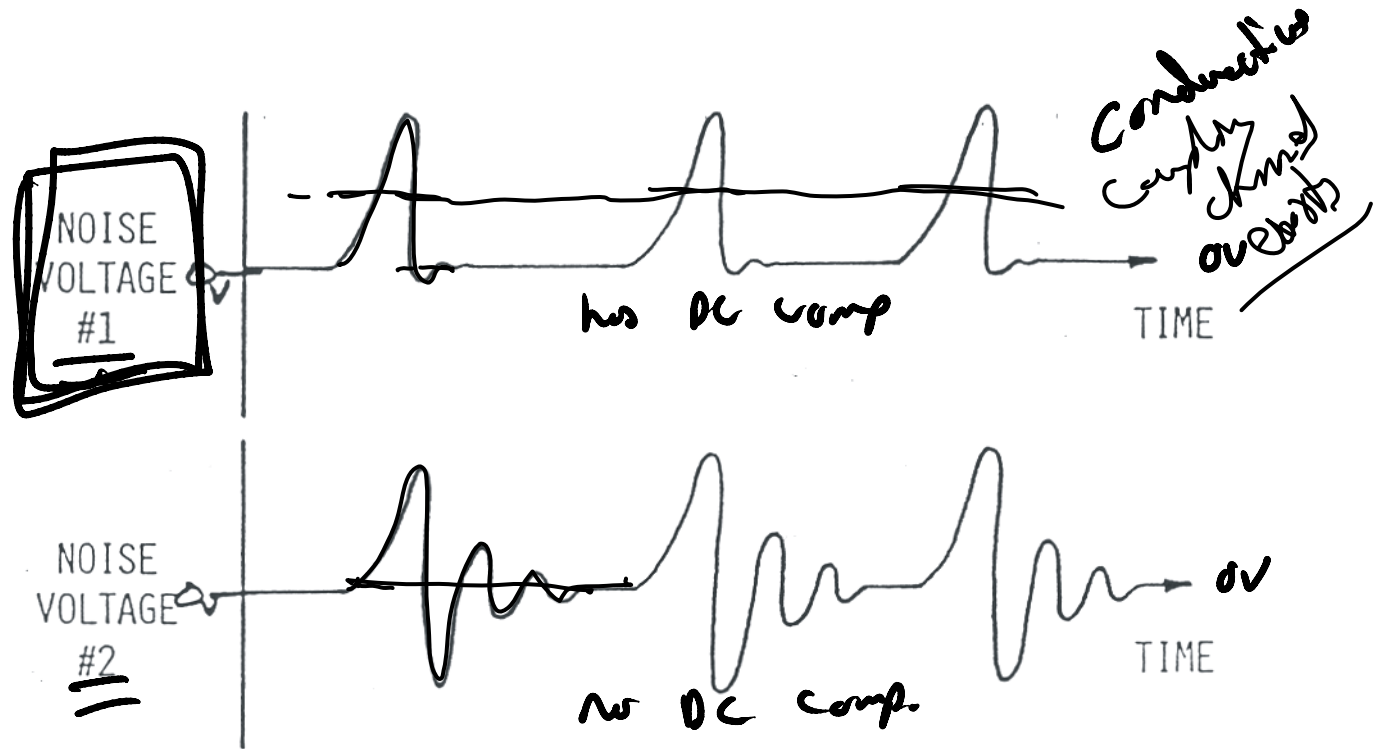


# Avoid Ground Loops





# Which waveform must be conductively coupled?



Why?



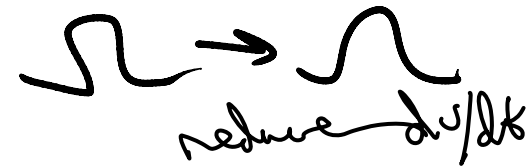
# Identifying Characteristics of Conductive Coupling

- + metallic contact is required
- + unaffected by people or cable movement
- + non-zero average value for waveform

Break Contact

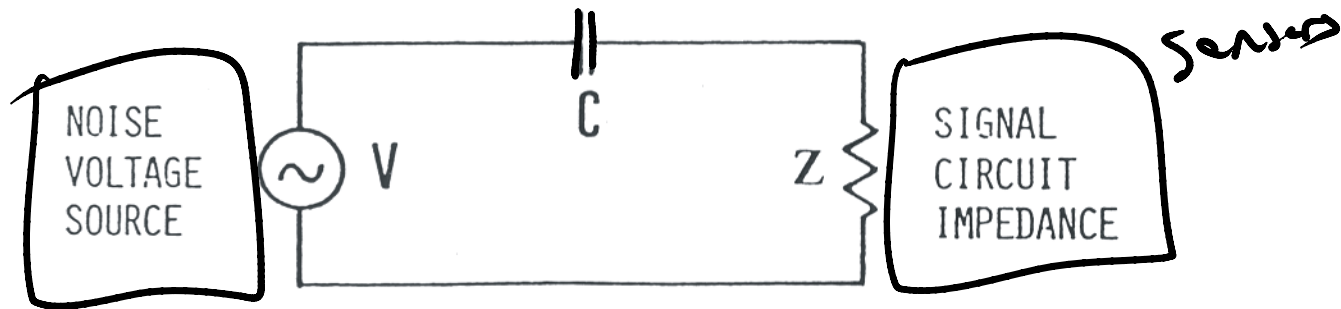
- repetitive waves back to full supply
- use P1 testing

tt  
eeee



# Capacitively coupled noise

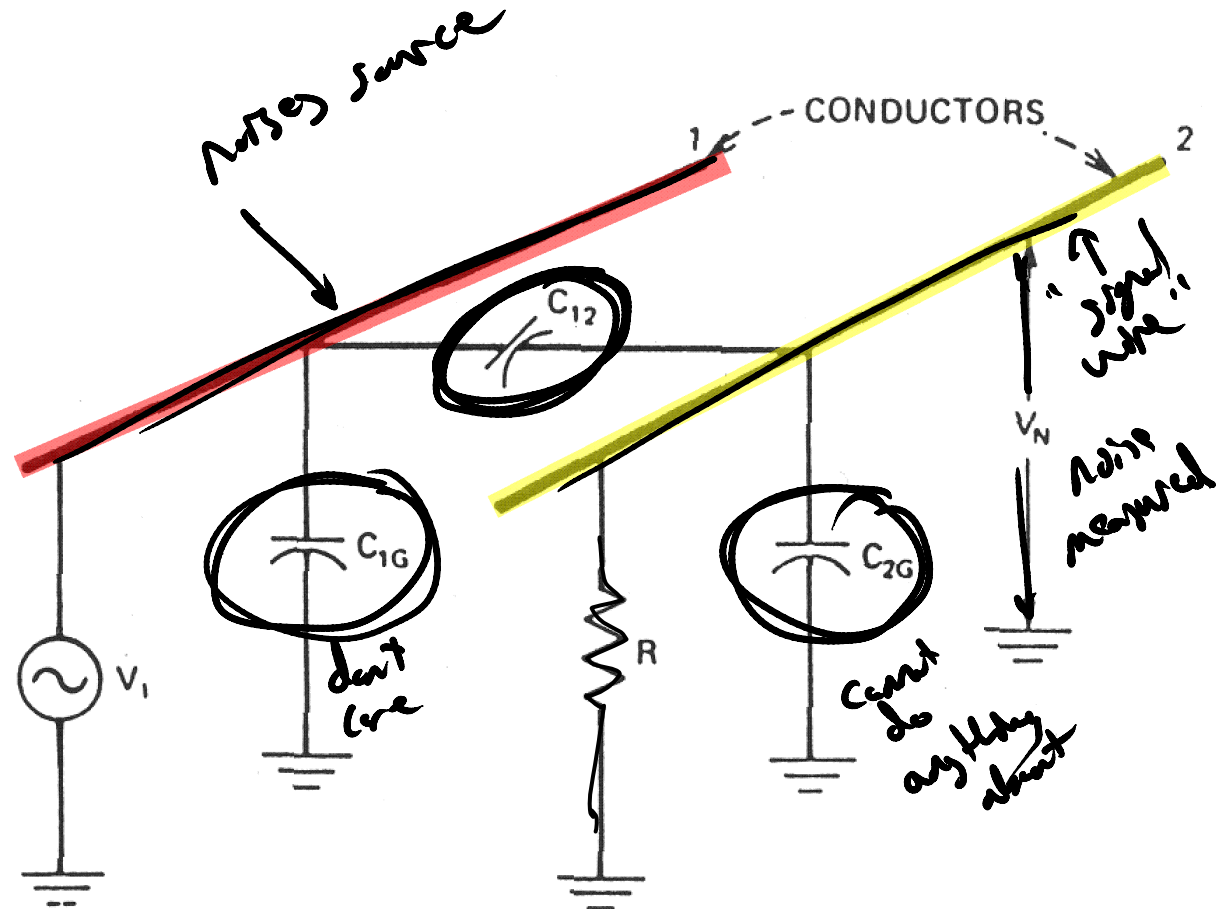
Coupling capacitance



Simplified circuit



# Physical Representation of capacitively coupled noise



PHYSICAL REPRESENTATION



# Equivalent circuit for capacitively coupled noise

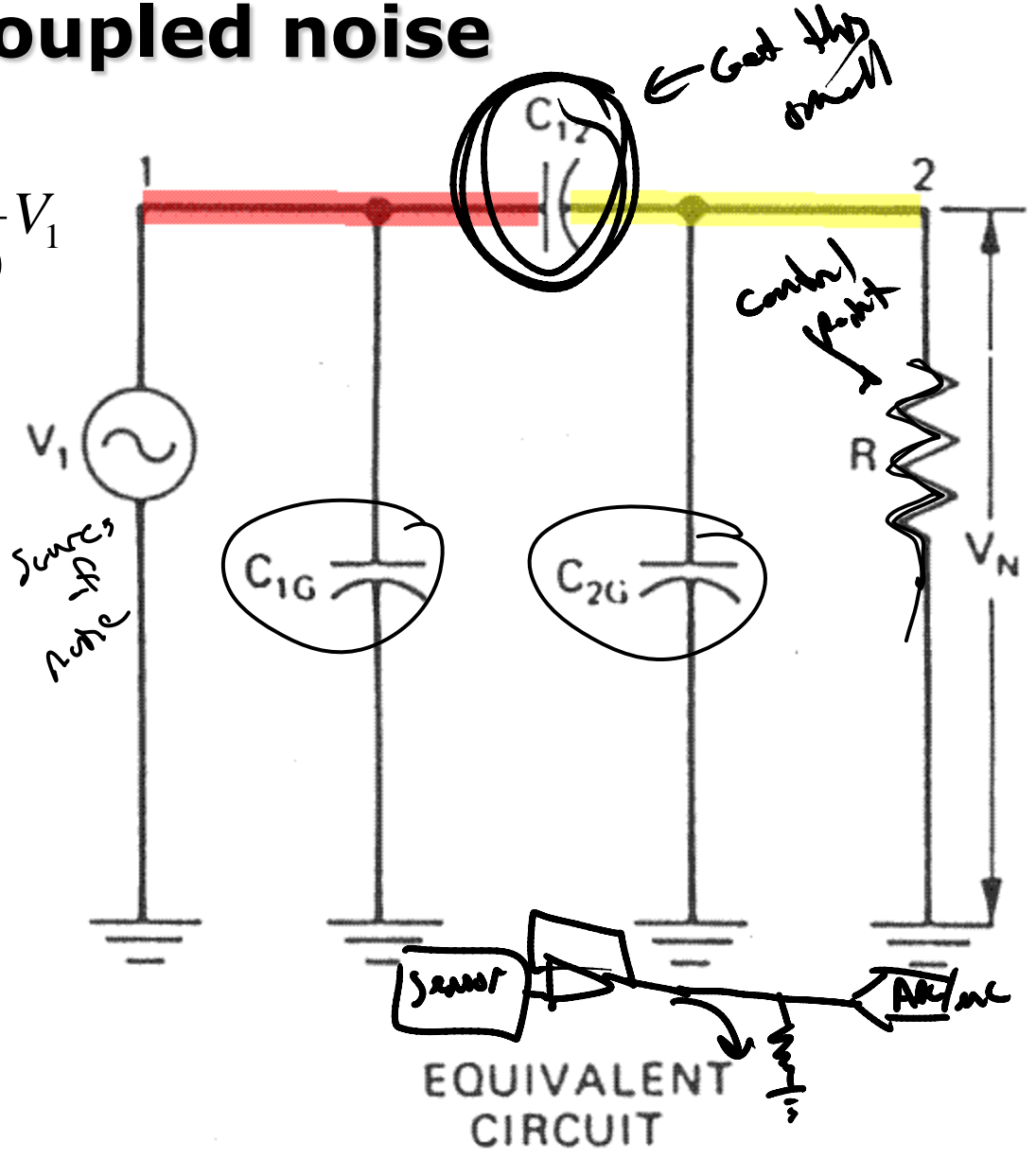
$$V_N = \frac{j\omega[C_{12}/(C_{12} + C_{2G})]}{j\omega + 1/R(C_{12} + C_{2G})} V_1$$

If  $R \gg \frac{1}{j\omega(C_{12} + C_{2G})}$   
*R is big*

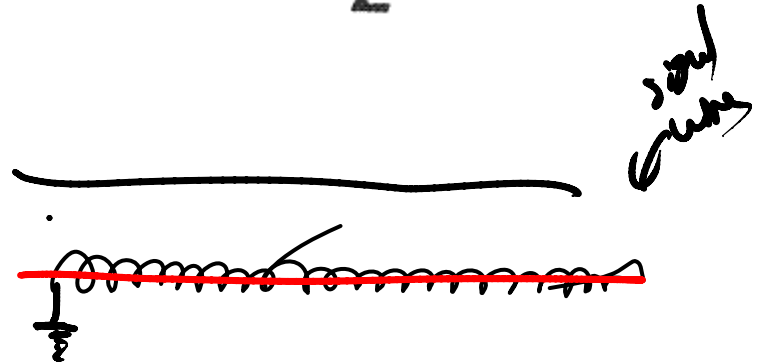
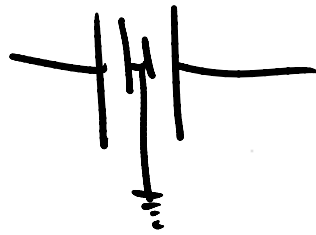
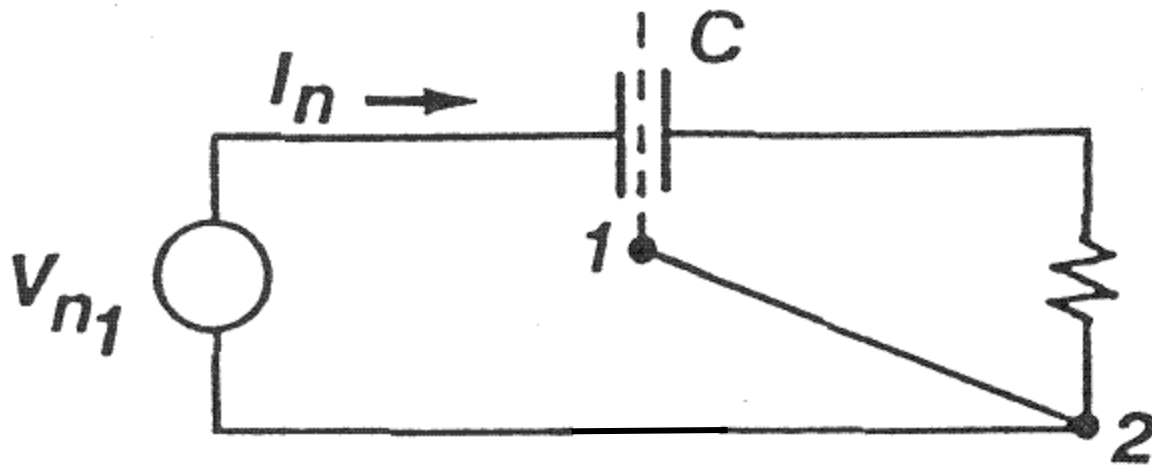
$$V_N = \frac{C_{12}}{(C_{12} + C_{2G})} V_1$$

If  $R \ll \frac{1}{j\omega(C_{12} + C_{2G})}$   
*R is small*

$$V_N = j\omega RC_{12} V_1$$



# Reducing Capacitively Coupled Noise



# Summary of capacitive noise reduction techniques

Reduce capacitive noise by:

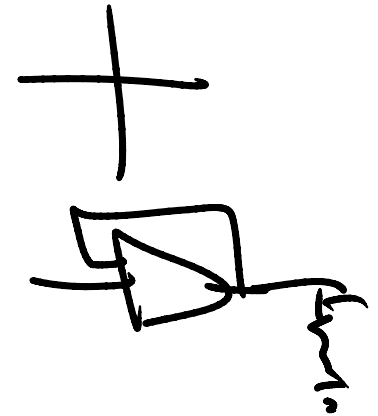
1) reduce capacitive coupling

2) increase circuit impedance

3) use shielding

— proper shield location  
— i.e. signals

— connect shield to gnd  
in one place only



# Isolation

Why do we need it?

- Conductive noise - have not paid attention to pur
  - large voltage differentials
  - fault isolation
  - min. leakage currents
- } critical  
in  
medical  
devices.

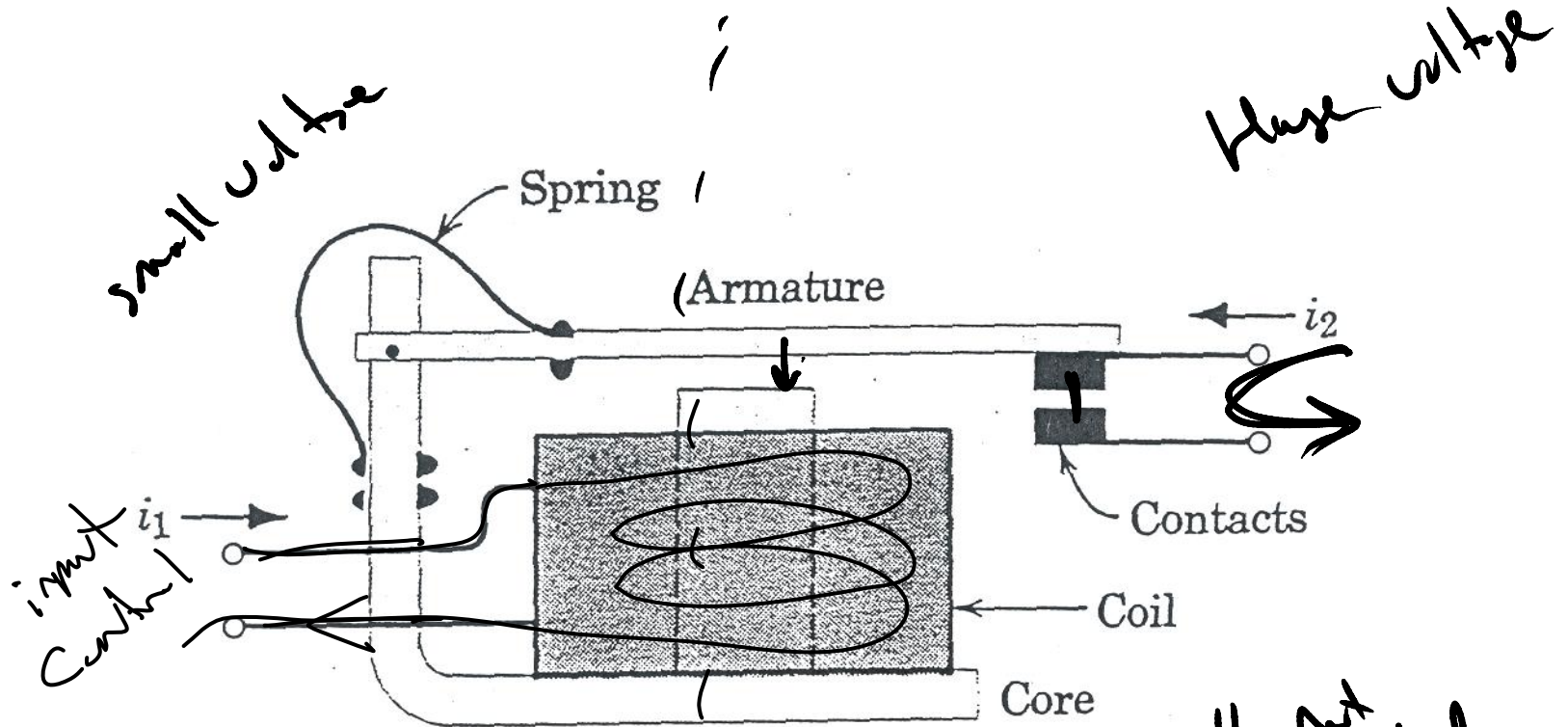
How do we do it?

- optical
  - magnetic
- } break the physical contact





# Isolation via magnetic coupling

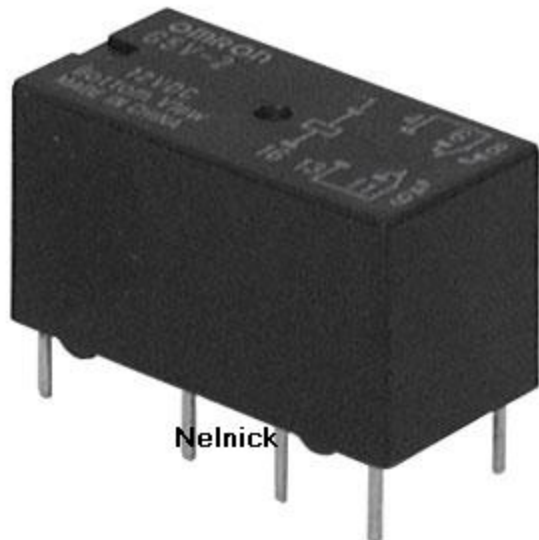
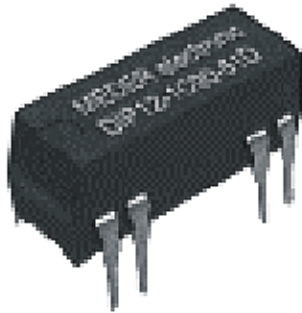


electrically not connected  
& like a mechanical transformer



# PCB mount miniature relays

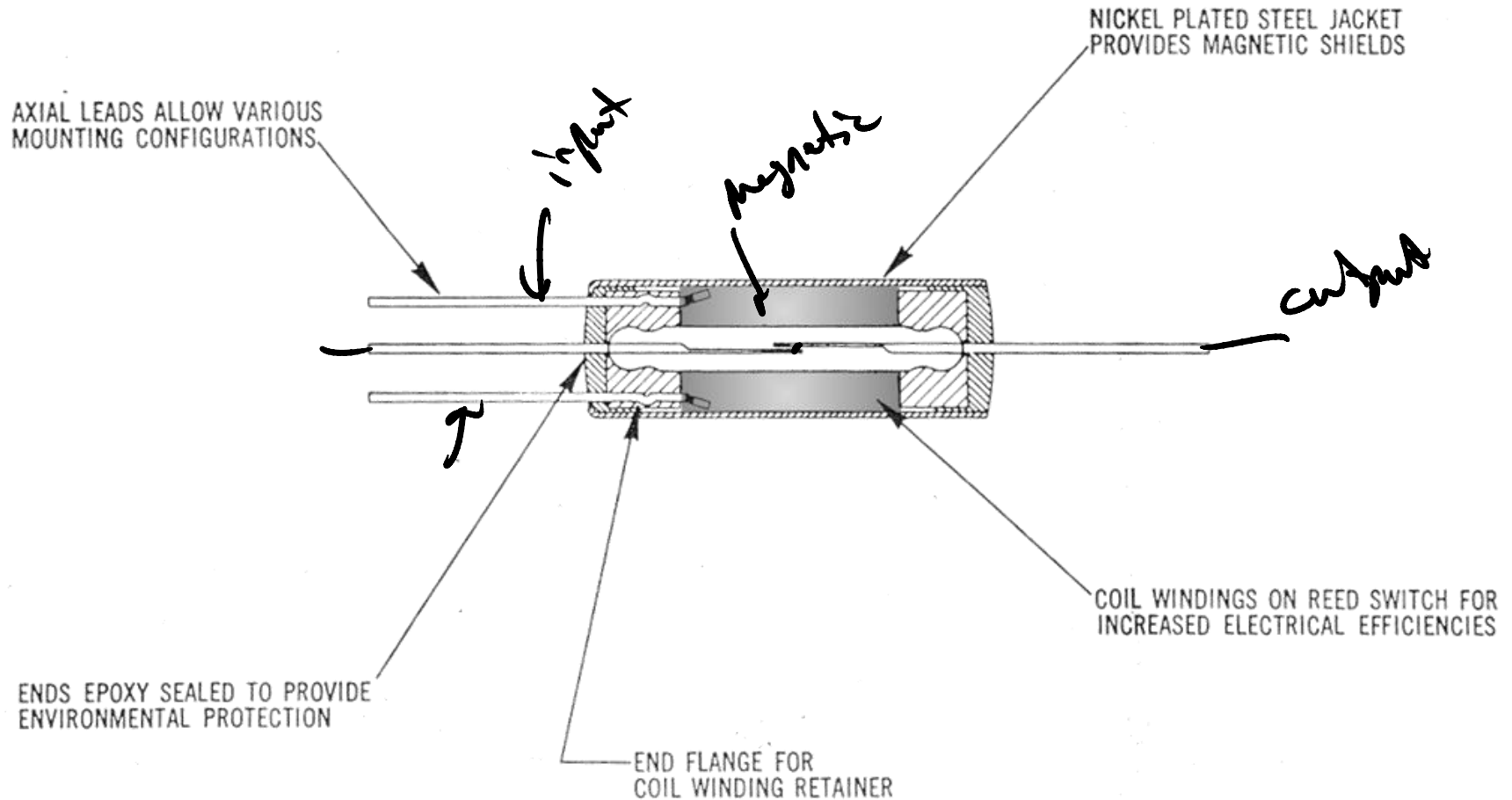
*Reed Relay*



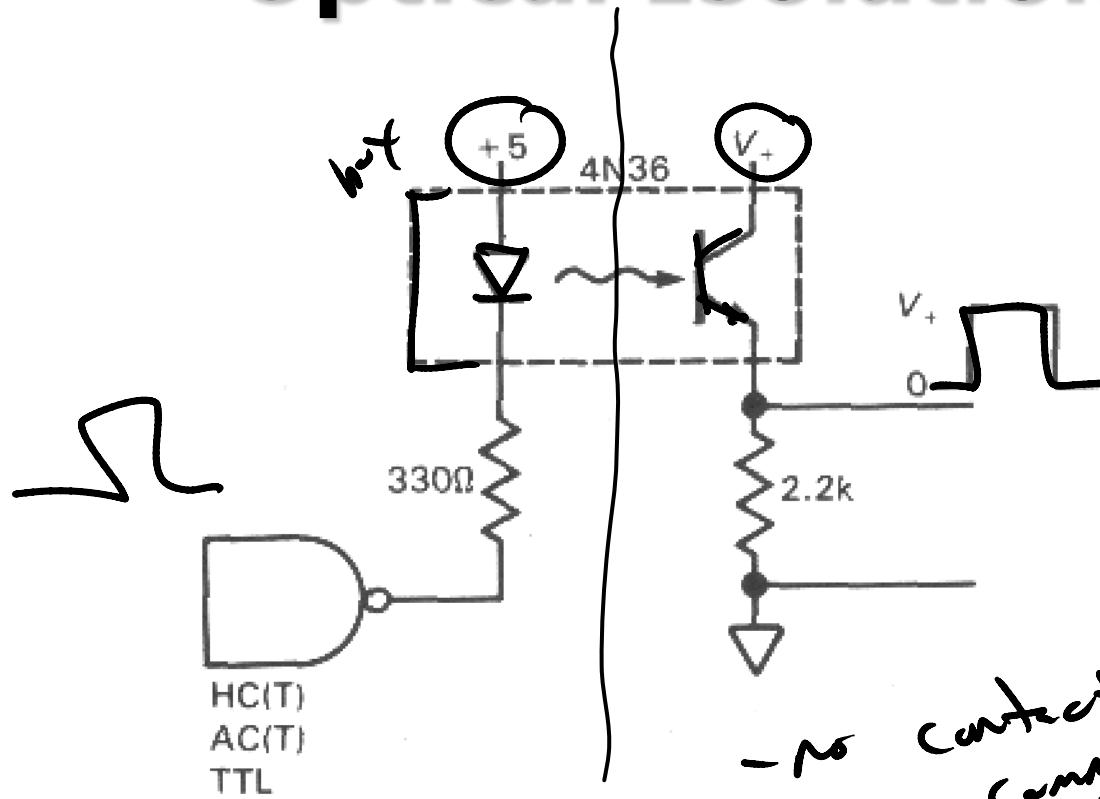
Nelnick



# Reed Relay construction



# Optical Isolation



- no contact
- no common level
- don't see cut difference



# GENERAL PURPOSE 6-PIN PHOTOTRANSISTOR OPTOCOUPPLERS

4N25  
4N37

4N26  
H11A1

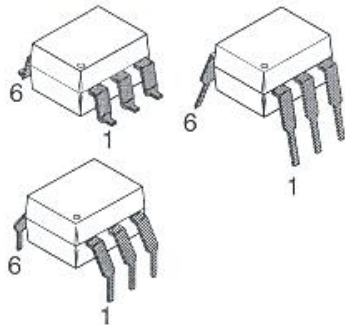
4N27  
H11A2

4N28  
H11A3

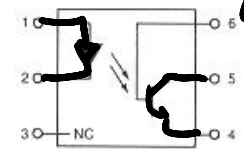
4N35  
H11A4

4N36  
H11A5

## WHITE PACKAGE (-M SUFFIX)

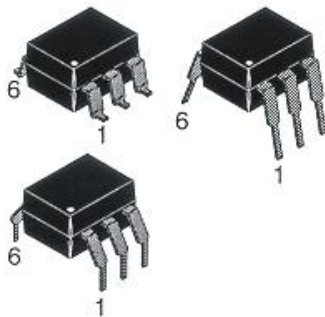


## SCHEMATIC



PIN 1. ANODE  
2. CATHODE  
3. NO CONNECTION  
4. EMITTER  
5. COLLECTOR  
6. BASE

## BLACK PACKAGE (NO -M SUFFIX)



4N25  
4N37

4N26  
H11A1

4N27  
H11A2

4N28  
H11A3

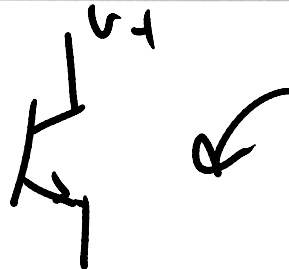
4N35  
H11A4

4N36  
H11A5

**ELECTRICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$  unless otherwise specified)

**INDIVIDUAL COMPONENT CHARACTERISTICS**

Parameter	Test Conditions	Symbol	Min	Typ*	Max	Unit
<b>EMITTER</b>						
Input Forward Voltage	( $I_F = 10\text{ mA}$ )	$V_F$		1.18	1.50	V
Reverse Leakage Current	( $V_R = 6.0\text{ V}$ )	$I_R$		0.001	10	$\mu\text{A}$
<b>DETECTOR</b>						
Collector-Emitter Breakdown Voltage	( $I_C = 1.0\text{ mA}$ , $I_F = 0$ )	$BV_{CEO}$	30	100		V
Collector-Base Breakdown Voltage	( $I_C = 100\text{ }\mu\text{A}$ , $I_F = 0$ )	$BV_{CBO}$	70	120		V
Emitter-Collector Breakdown Voltage	( $I_E = 100\text{ }\mu\text{A}$ , $I_F = 0$ )	$BV_{ECO}$	7	10		V
Collector-Emitter Dark Current	( $V_{CE} = 10\text{ V}$ , $I_F = 0$ )	$I_{CEO}$		1	50	nA
Collector-Base Dark Current	( $V_{CB} = 10\text{ V}$ )	$I_{CBO}$			20	nA
Capacitance	( $V_{CE} = 0\text{ V}$ , $f = 1\text{ MHz}$ )	$C_{CE}$		8		pF



4N25  
4N37

4N26  
H11A1

4N27  
H11A2

4N28  
H11A3

4N35  
H11A4

4N36  
H11A5

**TRANSFER CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$  Unless otherwise specified.)

DC Characteristic	Test Conditions	Symbol	Device	Min	Typ*	Max	Unit
<p>Current Transfer Ratio, Collector to Emitter</p> <p><math>I_C / I_F</math></p> <p><math>I_C \rightarrow I_F</math></p>	<p>(<math>I_F = 10\text{ mA}</math>, <math>V_{CE} = 10\text{ V}</math>)</p>	CTR	4N35 4N36 4N37	100			%
			H11A1 H11A5	50 30			
			4N25 4N26 H11A2 H11A3	20			
	( $I_F = 10\text{ mA}$ , $V_{CE} = 10\text{ V}$ , $T_A = -55^\circ\text{C}$ )		4N35 4N36 4N37	40			
	( $I_F = 10\text{ mA}$ , $V_{CE} = 10\text{ V}$ , $T_A = +100^\circ\text{C}$ )		4N35 4N36 4N37	40			



Collector-Emitter Saturation Voltage	$(I_C = 2 \text{ mA}, I_F = 50 \text{ mA})$	$V_{CE(SAT)}$	4N25 4N26 4N27 4N28		<i>min</i>	<i>max</i>	0.5	V
	$(I_C = 0.5 \text{ mA}, I_F = 10 \text{ mA})$		4N35 4N36 4N37			0.3		
			<del>H11A1</del> H11A2 H11A3 H11A4 H11A5				0.4	
AC Characteristic								
Non-Saturated Turn-on Time	$(I_F = 10 \text{ mA}, V_{CC} = 10 \text{ V}, R_L = 100\Omega)$ (Fig.20)	$T_{ON}$	4N25 4N26 4N27 4N28 H11A1 H11A2 H11A3 H11A4 H11A5		2			$\mu\text{s}$
Non Saturated Turn-on Time	$(I_C = 2 \text{ mA}, V_{CC} = 10 \text{ V}, R_L = 100\Omega)$ (Fig.20)	$T_{ON}$	4N35 4N36 4N37		2		10	$\mu\text{s}$

*Speed*

*switch in ~ 10  $\mu\text{s}$*





H11AA1

H11AA3

H11AA2

H11AA4

**DESCRIPTION**

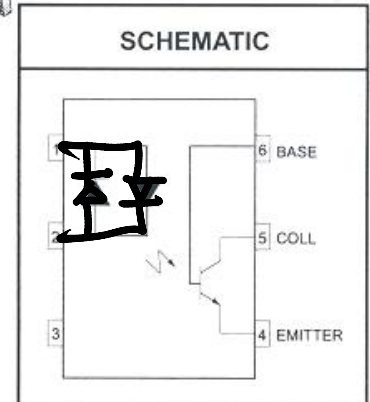
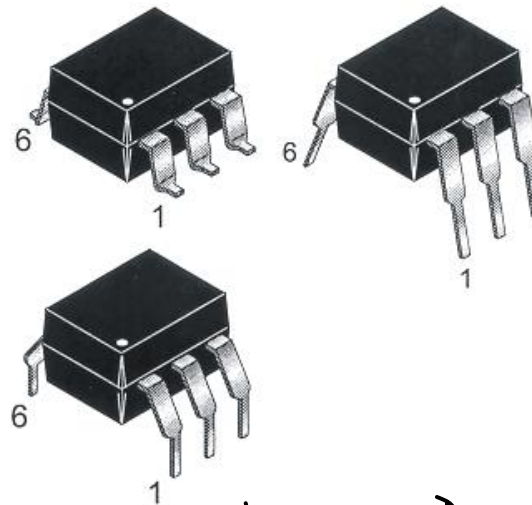
The H11AAX series consists of two gallium-arsenide infrared emitting diodes connected in inverse parallel driving a single silicon phototransistor output.

**FEATURES**

- Bi-polar emitter input
- Built-in reverse polarity input protection
- Underwriters Laboratory (UL) recognized — File #E90700
- VDE approved — File #E94766 (ordering option '300')

**APPLICATIONS**

- AC line monitor
- Unknown polarity DC sensor
- Telephone line interface



*- switch replacement  
- insensitive to polarity*



## DESCRIPTION

The CNX48U, H11BX, MOC8080 and TIL113 have a gallium arsenide infrared emitter optically coupled to a silicon planar photodarlington.

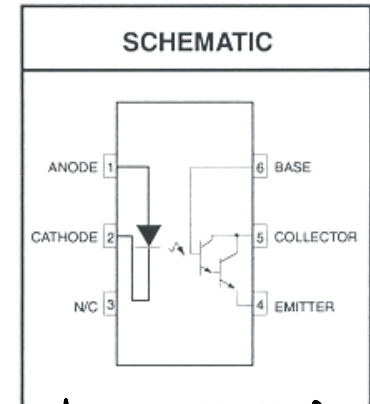
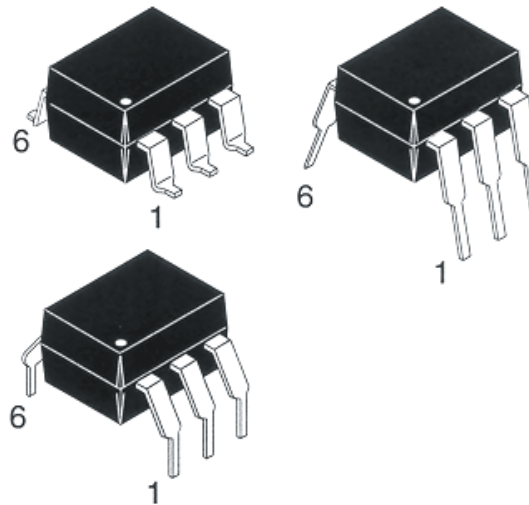
CNX48U	H11B1	H11B2	H11B255	H11B3
MOC8080	TIL113			

## FEATURES

- High sensitivity to low input drive current
- Meets or exceeds all JEDEC Registered Specifications
- VDE 0884 approval available as a test option  
-add option .300. (e.g., H11B1.300)

## APPLICATIONS

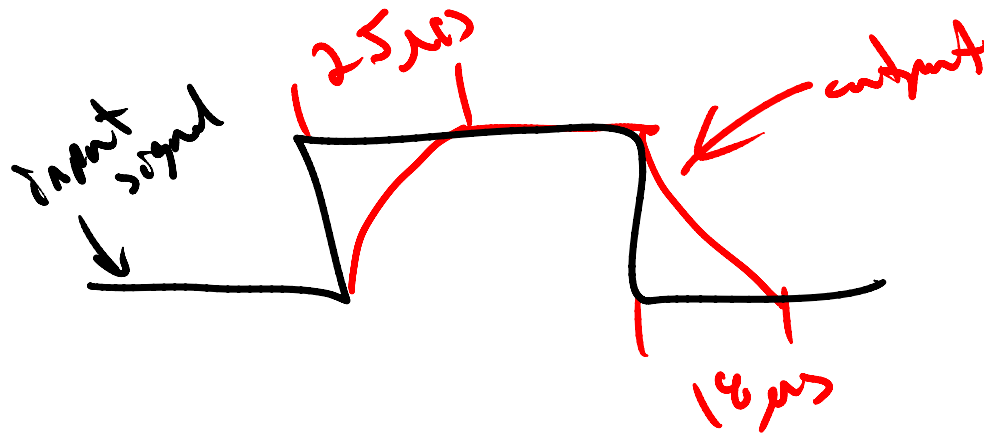
- Low power logic circuits
- Telecommunications equipment
- Portable electronics
- Solid state relays
- Interfacing coupling systems of different potentials and impedances.



*Higher current transfer ratio (CTA)  
~100%*



AC Characteristics						
Switching Times	$(I_C = 10 \text{ mA}, V_{CE} = 10 \text{ V})$ $(R_L = 100 \Omega)$ (Fig.7)	$t_{on}$	<del>H11B1</del> H11B2	25		
		$t_{off}$	H11B255 H11B3	18		
	$(I_F = 10 \text{ mA}, V_{CC} = 5 \text{ V})$ $(R_E = 100 \Omega), (R_{BE} = 1M\Omega)$ (Fig. 8)	$t_{on}$		3.5		
		$t_{off}$		36		
	$(I_F = 1 \text{ mA}, V_{CC} = 5 \text{ V})$ $(R_E = 1k\Omega), (R_{BE} = 10M\Omega)$ (Fig. 8)	$t_{on}$	CNX48U	70		
		$t_{off}$		190		
	$(I_F = 5 \text{ mA}, V_{CC} = 10 \text{ V})$ $(R_L = 100 \Omega)$ (Fig.7)	$t_{on}$	MOC8080	3.5		
		$t_{off}$		25		
	$(I_F = 200 \text{ mA}, I_C = 50 \text{ mA})$ $(V_{CC} = 10 \text{ V}) (R_L = 100 \Omega)$ (Fig.7)	$t_{on}$	TIL113	0.35	5	
		$t_{off}$		55	100	





# 6-Pin DIP Optoisolators Logic Output

The H11L1 and H11L2 have a gallium arsenide IRED optically coupled to a high-speed integrated detector with Schmitt trigger output. Designed for applications requiring electrical isolation, fast response time, noise immunity and digital logic compatibility.

- Guaranteed Switching Times —  $t_{on}, t_{off} < 4 \mu s$
- Built-In On/Off Threshold Hysteresis
- High Data Rate, 1 MHz Typical (NRZ)
- Wide Supply Voltage Capability
- Microprocessor Compatible Drive
- *To order devices that are tested and marked per VDE 0884 requirements, the suffix "V" must be included at end of part number. VDE 0884 is a test option.*

## Applications

- Interfacing Computer Terminals to Peripheral Equipment
- Digital Control of Power Supplies
- Line Receiver — Eliminates Noise
- Digital Control of Motors and Other Servo Machine Applications
- Logic to Logic Isolator
- Logic Level Shifter — Couples TTL to CMOS

**MAXIMUM RATINGS** ( $T_A = 25^\circ C$  unless otherwise noted)

**H11L1\***

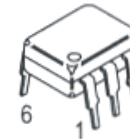
[IF(on) = 1.6 mA Max]

**H11L2**

[IF(on) = 10 mA Max]

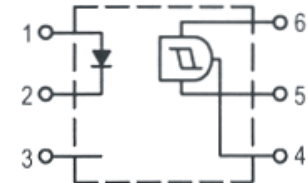
\*Motorola Preferred Device

STYLE 5 PLASTIC



STANDARD THRU HOLE  
CASE 730A-04

SCHEMATIC



# H11L1 H11L2

## ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ unless otherwise noted)(1)

Characteristic	Symbol	Min	Typ <sup>(1)</sup>	Max	Unit
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### INPUT LED

Reverse Leakage Current ( $V_R = 3\text{ V}$ , $R_L = 1\text{ M}\Omega$ )	$I_R$	—	0.05	10	$\mu\text{A}$
Forward Voltage ( $I_F = 10\text{ mA}$ ) ( $I_F = 0.3\text{ mA}$ )	$V_F$	— 0.75	1.2 0.95	1.5 —	Volts
Capacitance ( $V_R = 0\text{ V}$ , $f = 1\text{ MHz}$ )	C	—	18	—	$\text{pF}$

### OUTPUT DETECTOR

Operating Voltage	$V_{CC}$	3	—	15	Volts
Supply Current ( $I_F = 0$ , $V_{CC} = 5\text{ V}$ )	$I_{CC(\text{off})}$	—	1	5	$\text{mA}$
Output Current, High ( $I_F = 0$ , $V_{CC} = V_O = 15\text{ V}$ )	$I_{OH}$	—	—	100	$\mu\text{A}$

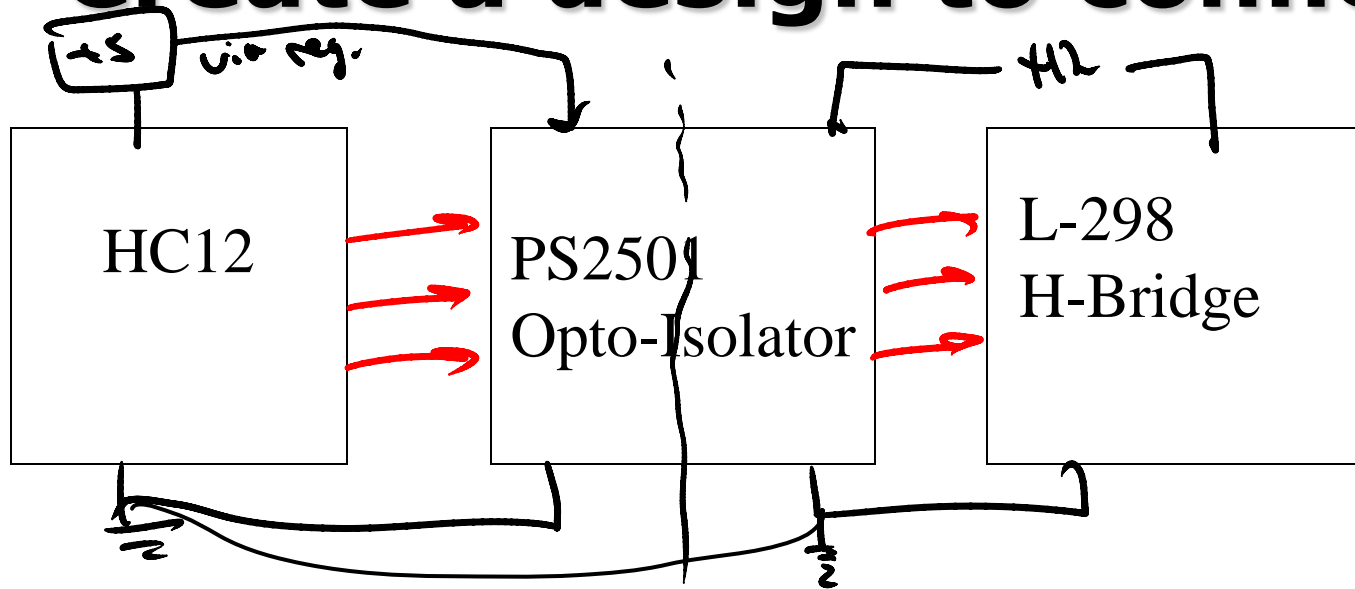
### COUPLED

Supply Current ( $I_F = I_{F(\text{on})}$ , $V_{CC} = 5\text{ V}$ )	$I_{CC(\text{on})}$	—	1.6	5	$\text{mA}$	
Output Voltage, Low ( $R_L = 270\ \Omega$ , $V_{CC} = 5\text{ V}$ , $I_F = I_{F(\text{on})}$ )	$V_{OL}$	—	0.2	0.4	Volts	
Threshold Current, ON ( $R_L = 270\ \Omega$ , $V_{CC} = 5\text{ V}$ )	$I_{F(\text{on})}$	H11L1 — H11L2	— —	1.2 — 1.6 10	$\text{mA}$	
Threshold Current, OFF ( $R_L = 270\ \Omega$ , $V_{CC} = 5\text{ V}$ )	$I_{F(\text{off})}$	H11L1 H11L2	0.3 0.3	0.75 —	$\text{mA}$	
Hysteresis Ratio ( $R_L = 270\ \Omega$ , $V_{CC} = 5\text{ V}$ )	$\frac{I_{F(\text{off})}}{I_{F(\text{on})}}$		0.5	0.75	0.9	
Isolation Voltage <sup>(2)</sup> 60 Hz, AC Peak, 1 second, $T_A = 25^\circ\text{C}$	$V_{ISO}$		7500	—	$\text{Vac(pk)}$	
Turn-On Time	$R_L = 270\ \Omega^{(3)}$ $V_{CC} = 5\text{ V}$ , $I_F = I_{F(\text{on})}$ $T_A = 25^\circ\text{C}$	$t_{on}$	—	1.2	4	$\mu\text{s}$
Fall Time		$t_f$	—	0.1	—	
Turn-Off Time		$t_{off}$	—	1.2	4	
Rise Time		$t_r$	—	0.1	—	

1. Always design to the specified minimum/maximum electrical limits (where applicable).
2. For this test, IRED Pins 1 and 2 are common and Output Gate Pins 4, 5, 6 are common.
3.  $R_L$  value effect on switching time is negligible.

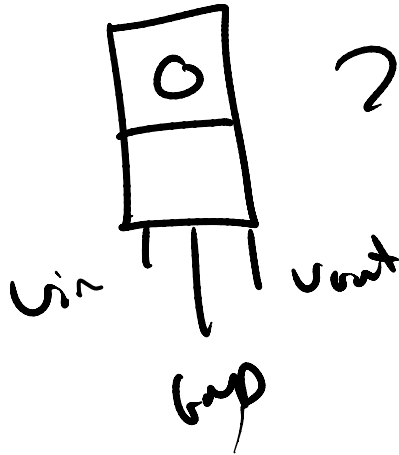


# Create a design to connect

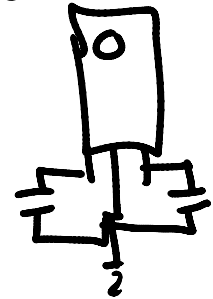
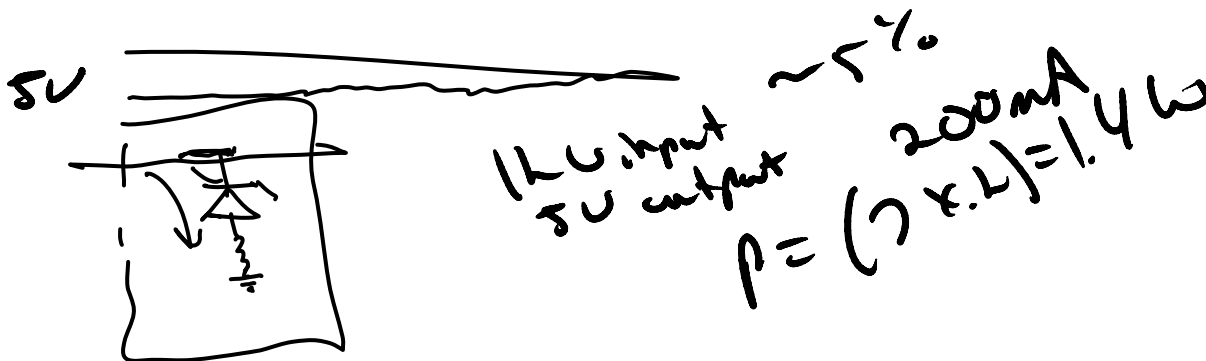
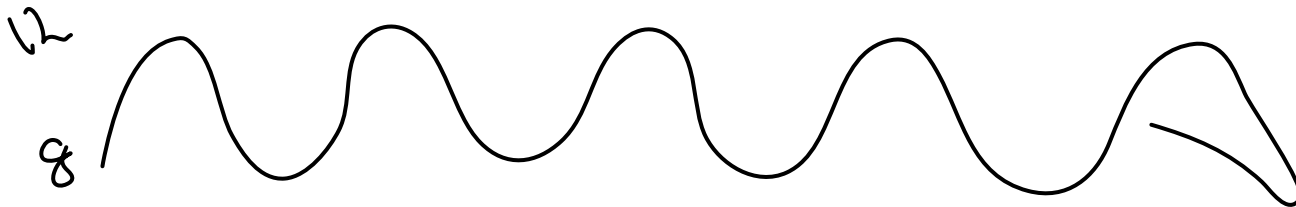


# Voltage Regulator

7805 5V Regulator



$V_{out} = 5V$   
 $i_A$   
 $V_{in} > 8V$   
 $V_{in} < V_{max}$



# Questions?

